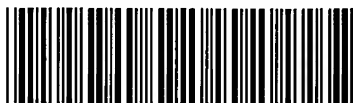


Search Notes

Application/Control No.

10/603,538

Examiner

James K. Trujillo

Applicant(s)/Patent under
Reexamination

DAYAN ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	4/5/2006	JKT